# XPS intensity calibration and validation using polyethylene and ionic liquids

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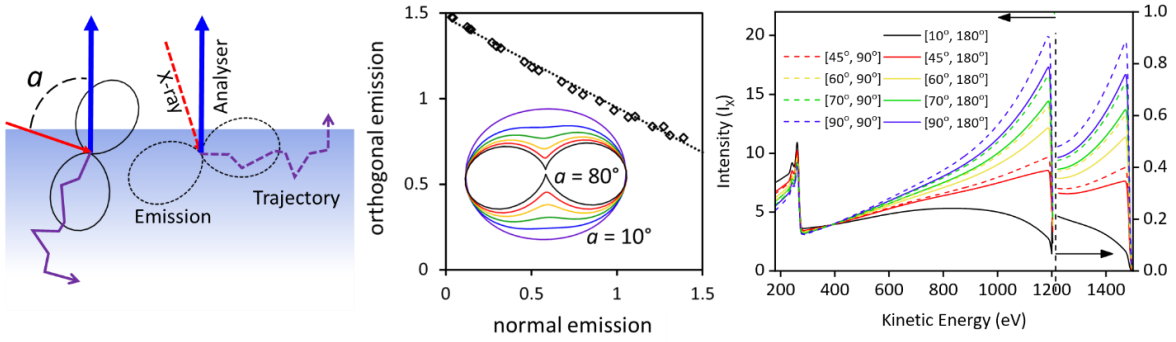


**Figure 1. Left:** Anisotropic emission of C 1s photoelectrons at different source-analyser angles. **Middle:** Ratio of normal to orthogonal photoelectron emission from C 1s for different source-analyser angles. **Right:** Polyethylene reference spectra for different instrument geometries.

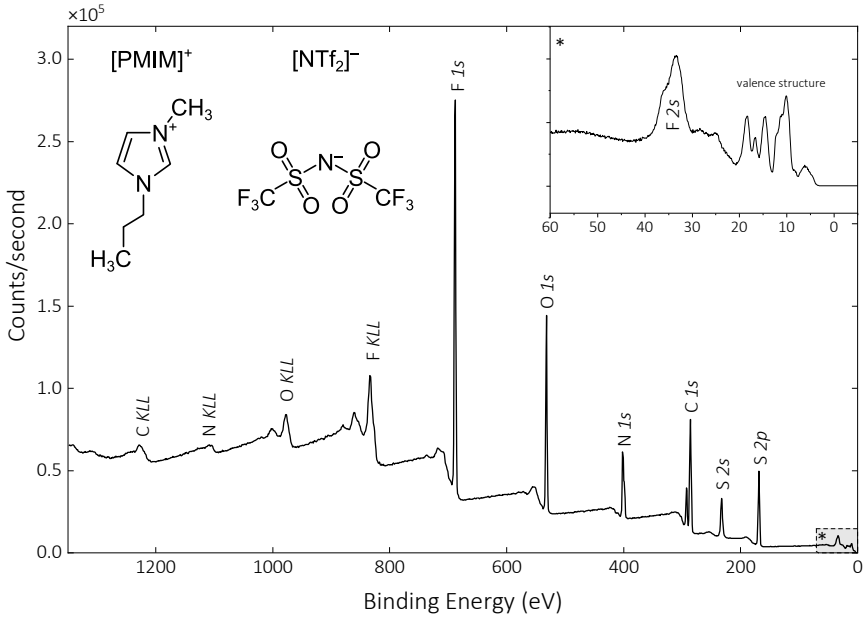


**Figure 2.** Survey spectrum of 1-propyl-3-methyl-imidazolium-bis(trifluoromethyl sulfonyl)imide and with inset chemical structure. **Inset Spectrum:** Extended valence spectrum showing F 2s.

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